# Inspect your defects

[M a c h i n e   L e a r n i n g
b a s e d   W a f e r
C l a s s i f i c a t i o n]

Resonate ?

Semiconductor chip makers face numerous issues due to the thousands of defects that go undetected everyday. There are cases of false positives and false negatives due to the high yield for companies using manual optical inspection for their screening of wafers.

Scalable, Efficient and Automated TechM Solution
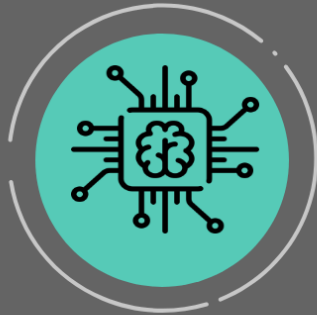
AI at the Edge Solution
(Training on cloud/Prediction at edge solution).

On Cloud based Solution
(Both training and classification on the edge)

Why Automate ?

Faster time to market: Real time classification leading to faster defect prediction helps in releasing the product faster to the market.

Improved Feedback Mechanism: Real time classification also helps in correcting and improving the affected processes.

Scalability: The solution can be scaled to any number of production and factory lines because of its independency from any network connection.

Capable of supporting never ending iterations: The Machine learning model can be retrained as and when there are new types of images.

Reduced operational cost: The reduced manual effort leads to minimal operational costs.

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